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## 8-Bit, 250 MSPS, 1.8 V Dual Analog-to-Digital Converter (ADC)

## Data Sheet

## FEATURES

Single 1.8 V supply operation
SNR: $\mathbf{4 9 . 3}$ dBFS at 200 MHz input at $\mathbf{2 5 0}$ MSPS
SFDR: 65 dBc at 200 MHz input at $\mathbf{2 5 0}$ MSPS
Low power: $\mathbf{3 1 4} \mathbf{~ m W}$ at 250 MSPS
On-chip reference and track-and-hold
1.2 V p-p analog input range for each channel

Differential input with 500 MHz bandwidth
LVDS-compliant digital output
DNL: $\pm 0.2$ LSB
Serial port control options
Offset binary, Gray code, or twos complement data format Optional clock duty cycle stabilizer
Built-in selectable digital test pattern generation
Pin-programmable power-down function
Available in 48-lead LFCSP

## APPLICATIONS

## Communications

Diversity radio systems
I/Q demodulation systems
Battery-powered instruments
Handheld scope meters
Low cost digital oscilloscopes
OTS: video over fiber

## GENERAL DESCRIPTION

The AD9284 is a dual 8-bit, monolithic sampling, analog-to-digital converter (ADC) that supports simultaneous operation and is optimized for low cost, low power, and ease of use. Each ADC operates at up to a 250 MSPS conversion rate with outstanding dynamic performance.

The ADC requires a single 1.8 V supply and an encode clock for full performance operation. No external reference components are required for many applications. The digital outputs are LVDS compatible.

The AD9284 is available in a Pb -free, 48 -lead LFCSP that is specified over the industrial temperature range of $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$.

## PRODUCT HIGHLIGHTS

1. Integrated Dual 8-Bit, 250 MSPS ADC.
2. Single 1.8 V Supply Operation with LVDS Outputs.
3. Power-Down Option Controlled via a Pin-Programmable Setting.


## AD9284* PRODUCT PAGE QUICK LINKS

Last Content Update: 02/23/2017

## COMPARABLE PARTS

View a parametric search of comparable parts.

## EVALUATION KITS

- AD9284 Evaluation Board


## DOCUMENTATION

## Application Notes

- AN-1142: Techniques for High Speed ADC PCB Layout
- AN-282: Fundamentals of Sampled Data Systems
- AN-345: Grounding for Low-and-High-Frequency Circuits
- AN-501: Aperture Uncertainty and ADC System Performance
- AN-586: LVDS Outputs for High Speed A/D Converters
- AN-715: A First Approach to IBIS Models: What They Are and How They Are Generated
- AN-737: How ADIsimADC Models an ADC
- AN-742: Frequency Domain Response of SwitchedCapacitor ADCs
- AN-756: Sampled Systems and the Effects of Clock Phase Noise and Jitter
- AN-827: A Resonant Approach to Interfacing Amplifiers to Switched-Capacitor ADCs
- AN-835: Understanding High Speed ADC Testing and Evaluation
- AN-851: A WiMax Double Downconversion IF Sampling Receiver Design
- AN-878: High Speed ADC SPI Control Software
- AN-905: Visual Analog Converter Evaluation Tool Version 1.0 User Manual
- AN-935: Designing an ADC Transformer-Coupled Front End


## Data Sheet

- AD9284: 8-Bit, 250 MSPS, 1.8 V Dual Analog-to-Digital Converter (ADC) Data Sheet


## User Guides

- UG-178: Evaluating the AD9284 Analog-to-Digital Converter


## TOOLS AND SIMULATIONS

- Visual Analog
- AD9284 IBIS Model


## REFERENCE MATERIALS

## Technical Articles

- MS-2210: Designing Power Supplies for High Speed ADC


## DESIGN RESOURCES

- AD9284 Material Declaration
- PCN-PDN Information
- Quality And Reliability
- Symbols and Footprints


## DISCUSSIONS

View all AD9284 EngineerZone Discussions.

## SAMPLE AND BUY

Visit the product page to see pricing options.

## TECHNICAL SUPPORT $\square$

Submit a technical question or find your regional support number.

## DOCUMENT FEEDBACK $\square$

Submit feedback for this data sheet.

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AD9284

## SPECIFICATIONS

## DC SPECIFICATIONS

AVDD $=1.8 \mathrm{~V}, \mathrm{DRVDD}=1.8 \mathrm{~V}, 1.0 \mathrm{~V}$ internal ADC reference, unless otherwise noted.
Table 1.

| Parameter ${ }^{1}$ | Temperature | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| RESOLUTION | Full | 8 |  |  | Bits |
| DC ACCURACY <br> Differential Nonlinearity <br> Integral Nonlinearity <br> No Missing Codes <br> Offset Error <br> Gain Error | Full <br> Full <br> Full <br> Full <br> Full | 0 | $\begin{aligned} & \pm 0.2 \\ & \pm 0.1 \\ & \text { Guaranteed } \\ & \pm 0.4 \\ & \pm 2.5 \end{aligned}$ | $\begin{gathered} \pm 0.4 \\ \pm 0.3 \\ \pm 2.1 \\ \pm 2.8 \end{gathered}$ | $\begin{aligned} & \text { LSB } \\ & \text { LSB } \\ & \text { \% FS } \\ & \text { \% FS } \end{aligned}$ |
| MATCHING CHARACTERISTICS <br> Offset Error <br> Gain Error | Full <br> Full |  | $\begin{aligned} & \pm 0.5 \\ & \pm 0.1 \end{aligned}$ | $\begin{aligned} & \pm 2.6 \\ & \pm 0.7 \end{aligned}$ | $\begin{aligned} & \% \text { FS } \\ & \% \text { FS } \end{aligned}$ |
| TEMPERATURE DRIFT Offset Error Gain Error | Full <br> Full |  | $\begin{aligned} & \pm 2 \\ & \pm 20 \end{aligned}$ |  | $\begin{aligned} & \mathrm{ppm} /{ }^{\circ} \mathrm{C} \\ & \mathrm{ppm} /{ }^{\circ} \mathrm{C} \end{aligned}$ |
| ANALOG INPUT <br> Input Span <br> Input Common-Mode Voltage Input Resistance (Differential) Input Capacitance (Differential) Full Power Bandwidth | Full <br> Full <br> Full <br> Full <br> Full |  | $\begin{aligned} & 1.2 \\ & 1.4 \\ & 16 \\ & 250 \\ & 700 \end{aligned}$ |  | $\begin{aligned} & \text { V p-p } \\ & \text { V } \\ & \mathrm{k} \Omega \\ & \mathrm{fF} \\ & \mathrm{MHz} \end{aligned}$ |
| VOLTAGE REFERENCE Internal Reference Input Resistance | Full <br> Full | 0.97 | $\begin{aligned} & 0.98 \\ & 3 \end{aligned}$ | 0.99 | $\begin{aligned} & \mathrm{V} \\ & \mathrm{k} \Omega \end{aligned}$ |
| POWER SUPPLIES <br> Supply Voltage <br> AVDD <br> DRVDD <br> Supply Current <br> IAvdD <br> IDRVDD | Full <br> Full <br> Full <br> Full | 1.7 1.7 | $\begin{aligned} & 1.8 \\ & 1.8 \\ & 124 \\ & 51 \end{aligned}$ | $\begin{aligned} & 1.9 \\ & 1.9 \\ & 128 \\ & 54 \end{aligned}$ | $\begin{aligned} & V \\ & V \\ & \mathrm{~mA} \\ & \mathrm{~mA} \end{aligned}$ |
| POWER CONSUMPTION <br> Sine Wave Input ${ }^{2}$ <br> Power-Down Power | Full <br> Full |  | $\begin{aligned} & 314 \\ & 0.3 \end{aligned}$ | $\begin{aligned} & 330 \\ & 1.7 \end{aligned}$ | $\begin{aligned} & \mathrm{mW} \\ & \mathrm{~mW} \end{aligned}$ |

[^0]
## AD9284

## AC SPECIFICATIONS

AVDD $=1.8 \mathrm{~V}$, DRVDD $=1.8 \mathrm{~V}, 1.0 \mathrm{~V}$ internal ADC reference, maximum sample rate, VIN $=-1.0 \mathrm{dBFS}$ differential input, unless otherwise noted.

Table 2.

| Parameter | Temperature | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| SIGNAL-TO-NOISE RATIO (SNR) $\begin{aligned} & \mathrm{fiN}_{\mathrm{IN}}=10.3 \mathrm{MHz} \\ & \mathrm{fiN}_{\mathrm{I}}=70 \mathrm{MHz} \\ & \mathrm{fiN}_{\mathrm{N}}=96.6 \mathrm{MHz} \\ & \mathrm{f}_{\mathrm{IN}}=220 \mathrm{MHz} \end{aligned}$ | $\begin{aligned} & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \\ & \text { Full } \\ & 25^{\circ} \mathrm{C} \end{aligned}$ | 48.7 | $\begin{aligned} & 49.3 \\ & 49.3 \\ & 49.3 \\ & 49.3 \end{aligned}$ |  | dBFS <br> dBFS <br> dBFS <br> dBFS |
| SIGNAL-TO-NOISE-AND-DISTORTION (SINAD) $\begin{aligned} & \mathrm{fiN}_{\mathrm{I}}=10.3 \mathrm{MHz} \\ & \mathrm{fiN}^{\prime}=70 \mathrm{MHz} \\ & \mathrm{fiN}=96.6 \mathrm{MHz} \\ & \mathrm{f}_{\mathrm{IN}}=220 \mathrm{MHz} \end{aligned}$ | $\begin{aligned} & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \\ & \text { Full } \\ & 25^{\circ} \mathrm{C} \end{aligned}$ | 48.5 | $\begin{aligned} & 49.2 \\ & 49.2 \\ & 49.2 \\ & 49.2 \end{aligned}$ |  | dBFS <br> dBFS <br> dBFS <br> dBFS |
| EFFECTIVE NUMBER OF BITS (ENOB) $\begin{aligned} & f_{\text {IN }}=10.3 \mathrm{MHz} \\ & \mathrm{fiN}_{\mathrm{I}}=70 \mathrm{MHz} \\ & \mathrm{fiN}^{2}=96.6 \mathrm{MHz} \\ & \mathrm{f}_{\mathrm{IN}}=220 \mathrm{MHz} \end{aligned}$ | $\begin{aligned} & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \\ & \text { Full } \\ & 25^{\circ} \mathrm{C} \end{aligned}$ | 7.8 | $\begin{aligned} & 7.9 \\ & 7.9 \\ & 7.9 \\ & 7.9 \end{aligned}$ |  | Bits <br> Bits <br> Bits <br> Bits |
| WORST SECOND OR THIRD HARMONIC $\begin{aligned} & \mathrm{fiN}_{\mathrm{IN}}=10.3 \mathrm{MHz} \\ & \mathrm{fiN}_{\mathrm{I}}=70 \mathrm{MHz} \\ & \mathrm{fiN}=96.6 \mathrm{MHz} \\ & \mathrm{f}_{\mathrm{IN}}=220 \mathrm{MHz} \end{aligned}$ | $\begin{aligned} & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \\ & \text { Full } \\ & 25^{\circ} \mathrm{C} \end{aligned}$ |  | $\begin{aligned} & -70 \\ & -70 \\ & -70 \\ & -65 \end{aligned}$ | -61 | dBc <br> dBc <br> dBc <br> dBc |
| SPURIOUS-FREE DYNAMIC RANGE (SFDR) $\begin{aligned} & f_{\mathrm{IN}^{\prime}}=10.3 \mathrm{MHz} \\ & \mathrm{fiN}^{\mathrm{IN}}=70 \mathrm{MHz} \\ & \mathrm{fiN}^{\prime}=96.6 \mathrm{MHz} \\ & \mathrm{f}_{\mathrm{IN}}=220 \mathrm{MHz} \end{aligned}$ | $\begin{aligned} & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \\ & \text { Full } \\ & 25^{\circ} \mathrm{C} \end{aligned}$ | 61 | $\begin{aligned} & 70 \\ & 70 \\ & 69 \\ & 65 \end{aligned}$ |  | dBc <br> dBc <br> dBc <br> dBc |
| WORST OTHER HARMONIC OR SPUR $\begin{aligned} & \mathrm{fiN}_{\mathrm{IN}}=10.3 \mathrm{MHz} \\ & \mathrm{fiN}_{\mathrm{IN}}=70 \mathrm{MHz} \\ & \mathrm{fiN}=96.6 \mathrm{MHz} \\ & \mathrm{f}_{\mathrm{IN}}=220 \mathrm{MHz} \end{aligned}$ | $\begin{aligned} & 25^{\circ} \mathrm{C} \\ & 25^{\circ} \mathrm{C} \\ & \text { Full } \\ & 25^{\circ} \mathrm{C} \end{aligned}$ |  | $\begin{aligned} & -71 \\ & -71 \\ & -70 \\ & -67 \end{aligned}$ | -64 | dBc <br> dBc <br> dBc <br> dBc |
| CROSSTALK | Full |  | -80 |  | dBc |

AD9284

## DIGITAL SPECIFICATIONS

$\mathrm{AVDD}=1.8 \mathrm{~V}, \mathrm{DRVDD}=1.8 \mathrm{~V}, 1.0 \mathrm{~V}$ internal ADC reference, full temperature, unless otherwise noted.
Table 3.

| Parameter ${ }^{1}$ | Temperature | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| CLOCK INPUTS (CLK+, CLK-) |  |  |  |  |  |
| Logic Compliance |  |  | LVDS/PECL |  |  |
| Internal Common-Mode Bias | Full |  | 1.2 |  | V |
| Differential Input Voltage ${ }^{2}$ | Full | 0.2 |  | 6 | $\checkmark \mathrm{p}$-p |
| Input Voltage Range | Full | AVDD - 0.3 |  | AVDD + 1.6 | V |
| High Level Input Voltage | Full | 1.2 |  | 3.6 | V |
| Low Level Input Voltage | Full | 0 |  | 0.8 | V |
| High Level Input Current | Full | -10 |  | +10 | $\mu \mathrm{A}$ |
| Low Level Input Current | Full | -10 |  | +10 | $\mu \mathrm{A}$ |
| Input Resistance (Differential) | $25^{\circ} \mathrm{C}$ |  | 20 |  | $\mathrm{k} \Omega$ |
| Input Capacitance | $25^{\circ} \mathrm{C}$ |  | 4 |  | pF |
| LOGIC INPUTS |  |  |  |  |  |
| CSB |  |  |  |  |  |
| High Level Input Voltage | Full | 1.2 |  | DRVDD + 0.3 | V |
| Low Level Input Voltage | Full | 0 |  | 0.8 | V |
| High Level Input Current | Full | -5 | -0.4 | +5 | $\mu \mathrm{A}$ |
| Low Level Input Current | Full | -80 | -63 | -50 | $\mu \mathrm{A}$ |
| Input Resistance | $25^{\circ} \mathrm{C}$ |  | 30 |  | $\mathrm{k} \Omega$ |
| Input Capacitance | $25^{\circ} \mathrm{C}$ |  | 2 |  | pF |
| SCLK, SDIO/PWDN, $\overline{\mathrm{OE}}$ |  |  |  |  |  |
| High Level Input Voltage | Full | 1.2 |  | DRVDD + 0.3 | V |
| Low Level Input Voltage | Full | 0 |  | 0.8 | V |
| High Level Input Current | Full | 50 | 57 | 70 | $\mu \mathrm{A}$ |
| Low Level Input Current | Full | -5 | -0.4 | +5 | $\mu \mathrm{A}$ |
| Input Resistance | $25^{\circ} \mathrm{C}$ |  | 30 |  | $\mathrm{k} \Omega$ |
| Input Capacitance | $25^{\circ} \mathrm{C}$ |  | 2 |  | pF |
| $\begin{aligned} & \text { DIGITAL OUTPUTS (D7+, D7- to D0+, D0-), LVDS } \\ & \text { DRVDD }=1.8 \mathrm{~V} \end{aligned}$ |  |  |  |  |  |
|  |  |  |  |  |  |
| Differential Output Voltage (Vod) | Full | 290 | 345 | 400 | mV |
| Output Offset Voltage (Vos) | Full | 1.15 | 1.25 | 1.35 | V |
| Output Coding (Default) |  |  | Offset binary |  |  |

[^1]
## SWITCHING SPECIFICATIONS

$\mathrm{AVDD}=1.8 \mathrm{~V}, \mathrm{DRVDD}=1.8 \mathrm{~V}$, maximum sample rate, -1.0 dBFS differential input, 1.0 V internal reference, unless otherwise noted.
Table 4.

| Parameter | Temperature | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| CLOCK INPUT PARAMETERS Input Clock Rate CLK Period (tcık) CLK Pulse Width High ( $\mathrm{t}_{\mathrm{CH}}$ ) | Full <br> Full <br> Full | $\begin{aligned} & 30 \\ & 4 \end{aligned}$ | 2 | 250 | MHz <br> ns ns |
| DATA OUTPUT PARAMETERS <br> Data Propagation Delay (tpD) DCO Propagation Delay (toco) DCO to Data Skew ( $\mathrm{t}_{\text {skew }}$ ) Pipeline Delay (Latency) Aperture Delay ( $\mathrm{t}_{\mathrm{A}}$ ) Aperture Uncertainty (Jitter, $\mathrm{t}_{\mathrm{J}}$ ) Wake-Up Time ${ }^{1}$ | Full <br> Full <br> Full <br> Full <br> Full <br> Full | -280 | $\begin{aligned} & 3.7 \\ & 3.7 \\ & -60 \\ & 10.5 \\ & 1.0 \\ & 0.1 \\ & 500 \\ & \hline \end{aligned}$ | +100 | ns <br> ns <br> ps <br> Cycles <br> ns <br> ps rms <br> us |
| OUT-OF-RANGE RECOVERYTIME | Full |  | 2 |  | Cycles |

${ }^{1}$ Wake-up time is dependent on the value of the decoupling capacitors.

## SPI TIMING SPECIFICATIONS

Table 5.

| Parameter | Description | Min | Typ | Max | Unit |
| :---: | :---: | :---: | :---: | :---: | :---: |
| SPI TIMING REQUIREMENTS |  |  |  |  |  |
| $\mathrm{t}_{\mathrm{DS}}$ | Setup time between the data and the rising edge of SCLK | 2 |  |  | ns |
| toh | Hold time between the data and the rising edge of SCLK | 2 |  |  | ns |
| tcık | Period of the SCLK | 40 |  |  | ns |
| ts | Setup time between CSB and SCLK | 2 |  |  | ns |
| $\mathrm{t}_{\mathrm{H}}$ | Hold time between CSB and SCLK | 2 |  |  | ns |
| $\mathrm{t}_{\text {HIGH }}$ | SCLK pulse width high | 10 |  |  | ns |
| tıow | SCLK pulse width low | 10 |  |  | ns |
| ten_solo | Time required for the SDIO pin to switch from an input to an output relative to the SCLK falling edge | 10 |  |  | ns |
| $\mathrm{t}_{\text {IIS_SDIO }}$ | Time required for the SDIO pin to switch from an output to an input relative to the SCLK rising edge | 10 |  |  | ns |

## Timing Diagram



Figure 2. Output Data Timing

## ABSOLUTE MAXIMUM RATINGS

Table 6.

| Parameter | Rating |
| :--- | :--- |
| Electrical | -0.3 V to +2.0 V |
| AVDD to AGND | -0.3 V to +2.0 V |
| DRVDD to DRGND | -0.3 V to +0.3 V |
| AGND to DRGND | -2.0 V to +2.0 V |
| AVDD to DRVDD | -0.3 V to DRVDD +0.3 V |
| D0+/D0- through D7+/D7- |  |
| to DRGND | -0.3 V to DRVDD +0.3 V |
| DCO+, DCO- to DRGND | -0.3 V to AVDD +0.2 V |
| CLK + CLK - to AGND | -0.3 V to AVDD +0.2 V |
| VIN $\pm \mathrm{A}, \mathrm{VIN} \pm$ B to AGND | -0.3 V to DRVDD +0.3 V |
| SDIO/PWDN to DRGND | -0.3 V to DRVDD +0.3 V |
| CSB to AGND | -0.3 V to DRVDD +0.3 V |
| SCLK to AGND | $-65^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ |
| Environmental | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ |
| Storage Temperature Range | $300^{\circ} \mathrm{C}$ |
| Operating Temperature Range |  |
| Lead Temperature | $150^{\circ} \mathrm{C}$ |
| $\quad$ (Soldering, 10 sec) |  |

Stresses above those listed under Absolute Maximum Ratings may cause permanent damage to the device. This is a stress rating only; functional operation of the device at these or any other conditions above those indicated in the operational section of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

## THERMAL RESISTANCE

$\theta_{\mathrm{JA}}$ is specified for the worst-case conditions, that is, a device soldered in a circuit board for surface-mount packages.

Table 7. Thermal Resistance

| Package Type | $\boldsymbol{\theta}_{\mathbf{J A}}$ | $\boldsymbol{\theta}_{\mathrm{Jc}}$ | Unit |
| :--- | :--- | :--- | :--- |
| 48-Lead LFCSP (CP-48-12) | 30.4 | 2.9 | ${ }^{\circ} \mathrm{C} / \mathrm{W}$ |

## ESD CAUTION

|  | ESD (electrostatic discharge) sensitive device. <br> Charged devices and circuit boards can discharge <br> without detection. Although this product features <br> patented or proprietary protection circuitry, damage <br> may occur on devices subjected to high energy ESD. <br> Therefore, proper ESD precautions should be taken to <br> avoid performance degradation or loss of functionality. |
| :--- | :--- |

## PIN CONFIGURATION AND FUNCTION DESCRIPTIONS



Figure 3. Pin Configuration
Table 8. Pin Function Descriptions

| Pin No. | Mnemonic | Type | Description |
| :---: | :---: | :---: | :---: |
| ADC Power Pins |  |  |  |
| $\begin{aligned} & 1,2,35,36,37,40,42 \\ & 44,45,48 \end{aligned}$ | AVDD | Supply | Analog Power Supply (1.8V Nominal). |
| 8,27 | DRVDD | Supply | Digital Output Driver Supply (1.8 V Nominal). |
| 7,28 | DRGND | Ground | Digital Output Ground. |
| 0 | AGND | Ground | Analog Ground. Pin 0 is the exposed thermal pad on the bottom of the package. This is the only ground connection, and it must be soldered to the PCB analog ground to ensure proper functionality and heat dissipation, noise, and mechanical strength benefits. |
| ADC Analog Pins |  |  |  |
| 39 | VIN+A | Input | Differential Analog Input Pin (+) for Channel A. |
| 38 | VIN-A | Input | Differential Analog Input Pin (-) for Channel A. |
| 46 | VIN+B | Input | Differential Analog Input Pin (+) for Channel B. |
| 47 | VIN-B | Input | Differential Analog Input Pin (-) for Channel B. |
| 43 | VREF | Input/output | Voltage Reference Input/Output. |
| 5 | RBIAS | Input/output | External Reference Bias Resistor. Connect $10 \mathrm{k} \Omega$ from RBIAS to AGND. |
| 41 | VCM | Output | Common-Mode Level Bias Output for Analog Inputs. |
| 34 | CLK+ | Input | ADC Clock Input-True. |
| 33 | CLK- | Input | ADC Clock Input-Complement. |
| Digital Input |  |  |  |
| 29 | $\overline{\mathrm{OE}}$ | Input | Digital Enable (Active Low) to Tristate Output Data Pins. |
| Digital Outputs |  |  |  |
| 26 | D7+ (MSB) | Output | Channel A/Channel B LVDS Output Data 7-True. |
| 25 | D7- (MSB) | Output | Channel A/Channel B LVDS Output Data 7-Complement. |
| 24 | D6+ | Output | Channel A/Channel B LVDS Output Data 6-True. |
| 23 | D6- | Output | Channel A/Channel B LVDS Output Data 6-Complement. |
| 22 | D5+ | Output | Channel A/Channel B LVDS Output Data 5-True. |
| 21 | D5- | Output | Channel A/Channel B LVDS Output Data 5-Complement. |
| 20 | D4+ | Output | Channel A/Channel B LVDS Output Data 4-True. |
| 19 | D4- | Output | Channel A/Channel B LVDS Output Data 4-Complement. |


| Pin No. | Mnemonic | Type | Description |
| :---: | :---: | :---: | :---: |
| 16 | D3+ | Output | Channel A/Channel B LVDS Output Data 3-True. |
| 15 | D3- | Output | Channel A/Channel B LVDS Output Data 3-Complement. |
| 14 | D2+ | Output | Channel A/Channel B LVDS Output Data 2-True. |
| 13 | D2- | Output | Channel A/Channel B LVDS Output Data 2-Complement. |
| 12 | D1+ | Output | Channel A/Channel B LVDS Output Data 1-True. |
| 11 | D1- | Output | Channel A/Channel B LVDS Output Data 1-Complement. |
| 10 | D0+ (LSB) | Output | Channel A/Channel B LVDS Output Data 0-True. |
| 9 | D0- (LSB) | Output | Channel A/Channel B LVDS Output Data 0-Complement. |
| 18 | DCO+ | Output | Channel A/Channel B LVDS Data Clock Output-True. |
| 17 | DCO- | Output | Channel A/Channel B LVDS Data Clock Output-Complement. |
| SPI Control Pins |  |  |  |
| 30 | SCLK | Input | SPI Serial Clock. |
| 31 | SDIO/PWDN | Input/output | SPI Serial Data I/O (SDIO)/Power-Down Input in External Mode (PWDN). |
| 32 | CSB | Input | SPI Chip Select (Active Low). |
| Do Not Connect |  |  |  |
| 3,4,6 | DNC | N/A | Do Not Connect. Do not connect to this pin. |

## TYPICAL PERFORMANCE CHARACTERISTICS

AVDD $=1.8 \mathrm{~V}, \mathrm{DRVDD}=1.8 \mathrm{~V}$, sample rate $=250 \mathrm{MSPS}, \mathrm{DCS}$ enabled, 1.2 V p-p differential input, VIN $=-1.0 \mathrm{dBFS}, 64 \mathrm{k}$ sample, $\mathrm{T}_{\mathrm{A}}=25^{\circ} \mathrm{C}$, unless otherwise noted.


Figure 4. Single-Tone FFT with $f_{I N}=4.3 \mathrm{MHz}$


Figure 5. Single-Tone FFT with $f_{I N}=220.3 \mathrm{MHz}$


Figure 6. SFDR/SNR vs. Input Amplitude (AIN) with $f_{I N}=2.2 \mathrm{MHz}$


Figure 7. Single-Tone FFT with $f_{I N}=96.6 \mathrm{MHz}$


Figure 8. Two-Tone FFT with $f_{I N 1}=29.1 \mathrm{MHz}$ and $f_{I N 2}=32.1 \mathrm{MHz}$


Figure 9. Two-Tone SFDR/IMD3 vs. Input Amplitude (AIN) with $f_{I_{N 1}}=29.1 \mathrm{MHz}$ and $f_{\mathrm{IN}_{2}}=32.1 \mathrm{MHz}$


Figure 10. SNRFS/SFDR vs Encode with $f_{I N}=2.4 \mathrm{MHz}$


Figure 11. DNL Error with $f_{I N}=4.3 \mathrm{MHz}$


Figure 12. INL Error with $f_{I N}=4.3 \mathrm{MHz}$

## EQUIVALENT CIRCUITS



Figure 13. Clock Inputs


Figure 14. Analog Inputs ( $V_{C M L}=\sim 1.4 \mathrm{~V}$ )



Figure 16. SCLK, $\overline{O E}$


Figure 17. SDIO


Figure 18. LVDS Output Driver

## THEORY OF OPERATION

The AD9284 is a pipeline-type converter. The input buffers are differential, and both sets of inputs are internally biased. This allows the use of ac or dc input modes. A sample-and-hold amplifier is incorporated into the first stage of the multistage pipeline converter core. The output staging block aligns the data, carries out error correction for the pipeline stages, and feeds that data to the output buffers. The two ADC channels are sampled simultaneously through a single encoding clock. All user-selected options are programmed through dedicated digital input pins or a serial port interface (SPI).

## ADC ARCHITECTURE

Each channel of the AD9284 consists of a differential input buffer followed by a sample-and-hold amplifier (SHA). The SHA is followed by a pipeline switched-capacitor ADC. The quantized outputs from each stage are combined into a final 8 -bit result in the digital correction logic. The pipelined architecture permits the first stage to operate on a new input sample, whereas the remaining stages operate on preceding samples.

Each stage of the pipeline, excluding the last, consists of a low resolution flash ADC connected to a switched-capacitor DAC and interstage residue amplifier (MDAC). The residue amplifier magnifies the difference between the reconstructed DAC output and the flash input for the next stage in the pipeline. One bit of redundancy is used in each stage to facilitate digital correction of flash errors. The last stage consists of a flash ADC.

The input stage contains a differential SHA that can be ac- or dc-coupled in differential or single-ended mode. The output staging block aligns the data, carries out error correction, and passes the data to the output buffers. The output buffers are powered from a separate supply, allowing adjustment of the output voltage swing. During power-down, the output buffers enter a high impedance state.

## ANALOG INPUT CONSIDERATIONS

The analog inputs of the AD9284 are differentially buffered. For best dynamic performance, the source impedances driving VIN+A, VIN+B, VIN-A, and VIN-B should be matched such that common-mode settling errors are symmetrical. The analog inputs are optimized to provide superior wideband performance and must be driven differentially. SNR and SINAD performance degrades significantly if the analog inputs are driven with a singleended signal.
A wideband transformer, such as Mini-Circuits ${ }^{\circ}$ ADT1-1WT, can provide the differential analog inputs for applications that require a single-ended-to-differential conversion. Both analog inputs are self-biased by an on-chip resistor divider to a nominal 1.4 V .

## Differential Input Configurations

Optimum performance is achieved when driving the AD9284 in a differential input configuration. For baseband applications, the ADA4937-1 differential driver provides excellent performance and a flexible interface to the ADC (see Figure 19). The output common-mode voltage of the AD9284 is easily set to 1.4 V , and the driver can be configured in a Sallen-Key filter topology to provide band limiting of the input signal.


Figure 19. Differential Input Configuration Using the ADA4937-1
The AD9284 can also be driven passively with a differential transformer-coupled input (see Figure 20). To bias the analog input, the VCM voltage can be connected to the center tap of the secondary winding of the transformer.


Figure 20. Differential Transformer-Coupled Configuration
The signal characteristics must be considered when selecting a transformer. Most RF transformers saturate at frequencies below a few megahertz (MHz). Excessive signal power can also cause core saturation, which leads to distortion.

## VOLTAGE REFERENCE

An internal differential voltage reference creates positive and negative reference voltages that define the 1.2 V p-p fixed span of the ADC core. This internal voltage reference can be adjusted by means of SPI control. It can also be driven externally with an off-chip stable reference. See the Memory Map Register Descriptions section for more details.

## RBIAS

The AD9284 requires the user to place a $10 \mathrm{k} \Omega$ resistor between the RBIAS pin and ground. This resistor, which is used to set the master current reference of the ADC core, should have a $1 \%$ tolerance.

## CLOCK INPUT CONSIDERATIONS

For optimum performance, clock the AD9284 sample clock inputs, CLK+ and CLK- with a differential signal. The signal is typically ac-coupled into the CLK+ and CLK- pins via a transformer or capacitors.

## Clock Input Options

The AD9284 has a very flexible clock input structure. The clock input can be an LVDS, LVPECL, or sine wave signal. Each configuration that is described in this section applies to CLK+ and CLK-.

Figure 21 and Figure 22 show the two preferred methods for clocking the AD9284. A low jitter clock source is converted from a single-ended signal to a differential signal using either an RF transformer or an RF balun. The back-to-back Schottky diodes across the transformer/balun secondary limit clock excursions into the AD9284 to approximately 0.8 V p-p differential.

This limit helps prevent the large voltage swings of the clock from feeding through to other portions of the AD9284, while preserving the fast rise and fall times of the signal that are critical to low jitter performance.


Figure 21. Transformer-Coupled Differential Clock


Figure 22. Balun-Coupled Differential Clock

If a low jitter clock source is not available, another option is to ac couple a differential PECL signal to the sample clock input pins, as shown in Figure 23. The AD9510/AD9511/AD9512/ AD9513/AD9514/AD9515/AD9516/AD9517 clock drivers offer excellent jitter performance.


Figure 23. Differential PECL Sample Clock
A third option is to ac couple a differential LVDS signal to the sample clock input pins, as shown in Figure 24. The AD9510/ AD9511/AD9512/AD9513/AD9514/AD9515/AD9516/AD9517 clock drivers offer excellent jitter performance.


Figure 24. Differential LVDS Sample Clock

## DIGITAL OUTPUTS

## Digital Output Enable Function ( $\overline{(\overline{O E})}$

The AD9284 has a flexible three-state ability for the digital output pins. The three-state mode is enabled using the $\overline{\mathrm{OE}}$ pin. When $\overline{\mathrm{OE}}$ is set to logic level high, the output drivers for both data buses are placed into a high impedance state.

## BUILT-IN SELF-TEST (BIST) AND OUTPUT TEST

The AD9284 includes a built-in self-test feature that is designed to enable verification of the integrity of each channel, as well as facilitate board level debugging. A built-in self-test (BIST) feature that verifies the integrity of the digital datapath of the AD9284 is included. Various output test options are also provided to place predictable values on the outputs of the AD9284.

## BUILT-IN SELF-TEST (BIST)

The BIST is a thorough test of the digital portion of the selected AD9284 signal path. Perform the BIST test after a reset to ensure that the part is in a known state. During BIST, data from an internal pseudorandom noise (PN) source is driven through the digital datapath of both channels, starting at the ADC block output. At the datapath output, CRC logic calculates a signature from the data. The BIST sequence runs for 512 cycles and then stops. When the test is completed, the BIST compares the signature results with a predetermined value. If the signatures match, the BIST sets Bit 0 of Register 0x0E, signifying that the test passed. If the BIST test fails, Bit 0 of Register 0x0E is cleared. The outputs are connected during this test, so the PN sequence can be observed as it runs.

Writing a value of $0 x 05$ to Register $0 x 0 \mathrm{E}$ runs the BIST. This enables Bit 0 (BIST enable) of Register 0x0E and resets the PN sequence generator, Bit 2 (BIST init) of Register 0x0E. At the completion of the BIST, Bit 0 of Register 0x0E is automatically cleared. The PN sequence can be continued from its last value by writing a 0 to Bit 2 of Register 0x0E. However, if the PN sequence is not reset, the signature calculation does not equal the predetermined value at the end of the test. At that point, the user must rely on verifying the output data.

## OUTPUT TEST MODES

The output test options are described in Table 12 at Address 0x0D. When an output test mode is enabled, the analog section of the ADC is disconnected from the digital back-end blocks, and the test pattern is run through the output formatting block. Some test patterns are subject to output formatting, and some are not. The PN generators from the PN sequence tests can be reset by setting Bit 4 or Bit 5 of Register 0x0D. These tests can be performed with or without an analog signal (if present, the analog signal is ignored), but they do require an encode clock. For more information, see the AN-877 Application Note, Interfacing to High Speed ADCs via SPI.

## SERIAL PORT INTERFACE (SPI)

The AD9284 serial port interface (SPI) allows the user to configure the converter for specific functions or operations through a structured register space provided inside the ADC. The SPI gives the user added flexibility and customization, depending on the application. Addresses are accessed via the serial port and can be written to or read from via the port. Memory is organized into bytes that can be further divided into fields, which are documented in the Memory Map section. For detailed operational information, see the AN-877 Application Note, Interfacing to High Speed ADCs via SPI.

## CONFIGURATION USING THE SPI

Three pins define the SPI of this ADC: SCLK, SDIO, and CSB (see Table 9). SCLK (a serial clock) is used to synchronize the read and write data presented from and to the ADC. SDIO (serial data input/output) is a dual-purpose pin that allows data to be sent to and read from the internal ADC memory map registers. CSB (chip select bar) is an active low control that enables or disables the read and write cycles.

Table 9. Serial Port Interface Pins

| Pin | Function |
| :--- | :--- |
| SCLK | Serial clock. A serial shift clock input that is used to <br> synchronize serial interface reads and writes. |
| SDIO | Serial data input/output. A dual-purpose pin that <br> typically serves as an input or an output, depending <br> on the instruction being sent and the relative position <br> in the timing frame. |
| CSB | Chip select bar. An active low control that gates the <br> read and write cycles. |

The falling edge of CSB, in conjunction with the rising edge of SCLK, determines the start of the framing. An example of the serial timing and its definitions can be found in Figure 25.

Other modes involving CSB are available. The CSB pin can be held low indefinitely, which permanently enables the device; this is called streaming. CSB can stall high between bytes to allow for additional external timing. When the CSB pin is tied high, SPI functions are placed in high impedance mode. This mode turns on any SPI pin secondary functions.
During the instruction phase, a 16-bit instruction is transmitted. Data follows the instruction phase, and its length is determined by the W0 and W1 bits, as shown in Figure 25.

All data is composed of 8-bit words. The first bit of the first byte in a multibyte serial data transfer frame indicates whether a read command or a write command is issued. This allows the serial data input/output (SDIO) pin to change direction from an input to an output at the appropriate point in the serial frame.
In addition to word length, the instruction phase determines whether the serial frame is a read or write operation, allowing the serial port to be used both to program the chip and to read the contents of the on-chip memory. If the instruction is a readback operation, the serial data input/output (SDIO) pin changes direction, from an input to an output, at the appropriate point in the serial frame.
Data can be sent in MSB-first mode or in LSB-first mode. MSB first is the default on power-up and can be changed via the SPI port configuration register. For more information about this and other features, see the AN-877 Application Note, Interfacing to High Speed ADCs via SPI.


Figure 25. Serial Port Interface Timing Diagram

## HARDWARE INTERFACE

The pins described in Table 9 constitute the physical interface between the programming device of the user and the serial port of the AD9284. The SCLK and CSB pins function as inputs when using the SPI interface. The SDIO pin is bidirectional, functioning as an input during write phases and as an output during readback.
The SPI interface is flexible enough to be controlled by either FPGAs or microcontrollers. One method for SPI configuration is described in detail in the AN-812 Application Note, Micro-controller-Based Serial Port Interface (SPI) Boot Circuit.
The SPI port should not be active during periods when the full dynamic performance of the converter is required. Because the SCLK, CSB, and SDIO signals are typically asynchronous to the ADC clock, noise from these signals can degrade converter performance. If the on-board SPI bus is used for other devices, it may be necessary to provide buffers between this bus and the AD9284 to prevent these signals from transitioning at the converter inputs during critical sampling periods.
SDIO/PWDN serves a dual function when the SPI interface is not being used. When the pin is strapped to AVDD or ground during device power-on, it is associated with a specific function. The mode selection table (see Table 10) describes the strappable functions that are supported on the AD9284.

Table 10. Mode Selection

| Pin | External Voltage | Configuration |
| :--- | :--- | :--- |
| SDIO/PWDN | AVDD (default) | Chip in full power-down |
|  | AGND | Normal operation |
| $\overline{\mathrm{OE}}$ | AVDD | Outputs in high impedance |
|  | AGND (default) | Outputs enabled |

## CONFIGURATION WITHOUT THE SPI

In applications that do not interface to the SPI control registers, the SDIO/PWDN pin serves as a standalone, CMOS-compatible control pin. When the device is powered up, it is assumed that the user intends to use the SDIO, SCLK, and CSB pins as static control lines for the output enable and power-down feature control. In this mode, connecting the CSB chip select to AVDD disables the serial port interface.

## SPI ACCESSIBLE FEATURES

Table 11 provides a brief description of the general features that are accessible via the SPI. These features are described in detail in the AN-877 Application Note, Interfacing to High Speed ADCs via SPI. The AD9284 part-specific features are described in detail in Table 12.

Table 11. Features Accessible Using the SPI

| Feature | Description |
| :--- | :--- |
| Mode | Allows the user to set either power-down mode <br> or standby mode <br> Allows the user to access the DCS via the SPI |
| Clock | Allows the user to digitally adjust the converter <br> offset <br> Allows the user to set test modes to have known <br> data on output bits |
| Test I/O | Allows the user to set up outputs <br> Output Mode <br> Output Phase <br> Output Delay <br> Voltage <br> Reference | | Allows the user to set the output clock polarity |
| :--- |
| Allows the user to vary the DCO delay |

## MEMORY MAP

## READING THE MEMORY MAP REGISTER TABLE

Each row in the memory map register table (see Table 12) has eight bit locations. The memory map is roughly divided into three sections: the chip configuration registers (Address 0x00 to Address 0x02), the device index and transfer registers (Address 0 x 05 and Address 0 xFF ), and the program registers (Address 0x08 to Address 0x25).

Table 12 documents the default hexadecimal value for each hexadecimal address shown. The column with the heading Bit 7 (MSB) is the start of the default hexadecimal value given. For more information on this function and others, see the AN-877 Application Note, Interfacing to High Speed ADCs via SPI. This document details the functions controlled by Register $0 \times 00$ to Register 0xFF.

## Open Locations

All address and bit locations that are not included in the SPI map are not currently supported for this device. Unused bits of a valid address location should be written with 0 s. Writing to these locations is required only when part of an address location is open. If the entire address location is open, it is omitted from the SPI map (for example, Address 0x13) and should not be written.

## Default Values

After the AD9284 is reset, critical registers are loaded with default values. The default values for the registers are given in the memory map register table (see Table 12).

## Logic Levels

An explanation of logic level terminology follows:

- "Bit is set" is synonymous with "bit is set to Logic 1" or "writing Logic 1 for the bit."
- "Bit is cleared" is synonymous with "bit is set to Logic 0 " or "writing Logic 0 for the bit."


## Transfer Register Map

Address $0 \times 08$ to Address $0 \times 38$ are shadowed. Writes to these addresses do not affect part operation until a transfer command is issued by writing $0 \times 01$ to Address 0 xFF , setting the transfer bit. Setting the transfer bit allows these registers to be updated internally and simultaneously. The internal update takes place when the transfer bit is set, and then the bit autoclears.

## Channel-Specific Registers

Some channel setup functions can be programmed differently for each channel. In these cases, channel address locations are internally duplicated for each channel. These registers and bits are designated in the memory map register table as local. These local registers and bits can be accessed by setting the appropriate Channel A (Bit 0) or Channel B (Bit 1) bits in Register 0x05.
If both bits are set, the subsequent write affects the registers of both channels. In a read cycle, set only Channel A or Channel B to read one of the two registers. If both bits are set during a SPI read cycle, the part returns the value for Channel A. Registers and bits designated as global in the memory map register table affect the entire part or the channel features for which independent settings are not allowed between channels. The settings in Register $0 \times 05$ do not affect the global registers and bits.

## MEMORY MAP REGISTER TABLE

All address and bit locations that are not included in Table 12 are not currently supported for this device.
Table 12. Memory Map Registers

| Addr <br> (Hex) | Register Name | Bit 7 <br> (MSB) | Bit 6 | Bit 5 | Bit 4 | Bit 3 | Bit 2 | Bit 1 | $\begin{aligned} & \text { Bit } 0 \\ & \text { (LSB) } \end{aligned}$ | Default Value (Hex) | Default <br> Notes/ <br> Comments |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| Chip Configuration Registers |  |  |  |  |  |  |  |  |  |  |  |
| 0x00 | SPI port configuration | 0 | LSB first | Soft reset | 1 | 1 | Soft reset | LSB first | 0 | 0x18 | Nibbles are mirrored so that LSB-first or MSB-first mode registers correctly, regardless of shift mode |
| 0x01 | Chip ID (global) | 8-bit chip ID |  |  |  |  |  |  |  | 0x0A | Unique chip ID used to differentiate devices; read only |
| 0x02 | Chip grade (global) | Open |  | Speed grade ID $000=250$ MSPS |  | Open |  |  |  | $0 \times 00$ | Unique speed grade ID is used to differentiate devices; read only |
| Device Index and Transfer Registers |  |  |  |  |  |  |  |  |  |  |  |
| 0x05 | Device Index A | Open |  |  |  |  |  | ADC B default | ADC A default | 0xFF | Bits are set to determine which on-chip device receives the next write command; default is all devices on the chip |
| 0xFF | Transfer | Open |  |  |  |  |  |  | Transfer | 0xFF | Synchronous transfer of data from the master shift register to the slave |
| Program Registers (May or may not be indexed by device index) |  |  |  |  |  |  |  |  |  |  |  |
| 0x08 | Modes (global) | Open |  |  |  |  | Internal power-down mode 00: chip run <br> 01: full power-down <br> 10: reserved <br> 11: reserved |  |  | $0 \times 00$ | Determines various generic modes of chip operation |
| $0 \times 09$ | Clock (global) | Open |  |  |  |  |  | Clock boost | Duty cycle stabilizer | $0 \times 01$ |  |
| 0x0D | Test mode (local) |  | Open | Reset PN23 gen | Reset PN9 gen | Open | Output test mode000: off001: midscale short010: +FS short011:-FS short100: checkerboard output101: PN23 sequence110: PN9 sequence111: one-/zero-word toggle |  |  | 0x00 | When test mode is set, test data is placed on the output pins in place of normal data |
| 0x0E | BIST (local) | Open |  |  |  |  | BIST init | Open | BIST enable | 0x00 | BIST mode config |


| Addr (Hex) | Register <br> Name | Bit 7 <br> (MSB) | Bit 6 | Bit 5 | Bit 4 | Bit 3 | Bit 2 | Bit 1 | $\begin{aligned} & \text { Bit } 0 \\ & \text { (LSB) } \end{aligned}$ | Default Value (Hex) | Default <br> Notes/ <br> Comments |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
| 0x0F | ADC input (global/local) | Open |  |  |  |  | Analog disconnect (local) | Commonmode input enable (global) | Open | 0x00 |  |
| 0x10 | Offset (local) | Open |  |  |  | $\begin{aligned} & \text { Offset adjust (twos complement format) } \\ & \qquad \begin{array}{c} 0111:+7 \\ 0110:+6 \\ \ldots \\ 0001:+1 \\ 0000: 0 \\ 1111:-1 \\ \ldots \\ 1001:-7 \\ 1000:-8 \end{array} \end{aligned}$ |  |  |  | 0x00 | Device offset trim |
| 0x14 | Output mode (local) | Open |  |  | Output enable | Open | Output invert | Data form 00: offse 01: twos 10: Gray 11: reser | t select <br> inary <br> mplement <br> de <br> d | 0x00 | Configures the outputs and the format of the data |
| 0x16 | Output phase (global) | DCO invert | Open |  |  |  |  |  |  | 0x00 |  |
| 0x18 | Voltage reference (global) | Open |  |  | Voltage reference and input full-scale adjustment (see Table 13) |  |  |  |  | 0x00 | Selects/ adjusts V VeF |
| 0×24 | MISR LSB <br> (local) | LSBs of multiple input shift register (MISR) |  |  |  |  |  |  |  | 0x00 | MISR least significant byte; read only |
| 0x25 | MISR MSB (local) | MSBs of multiple input shift register (MISR) |  |  |  |  |  |  |  | 0x00 | MISR most significant byte; read only |

AD9284

## MEMORY MAP REGISTER DESCRIPTIONS

For more information about functions controlled in Register 0x00 to Register 0xFF, see the AN-877 Application Note, Interfacing to High Speed ADCs via SPI.

Voltage Reference (Register 0x18)
Bits[7:5]-Reserved
Bits[4:0]-Voltage Reference
Bits[4:0] scale the internally generated voltage reference and, consequently, the full scale of the analog input. Within this register, the reference driver can be configured to be more easily driven externally by reducing the capacitive loading.

The relationship between the $\mathrm{V}_{\text {ref }}$ voltage and the input full scale is described by Equation 1. See Table 13 for a complete list of register settings.

Input_Full_Scale $=V_{\text {REF }} \times 1.2$

Table 13. $\mathrm{V}_{\text {ref }}$ and Input Full Scale (Register 0x18)

| Value | V $_{\text {REF }}$ (V) | Full Scale (V) |
| :--- | :--- | :--- |
| 0x14 | 0.844 | 1.013 |
| 0x15 | 0.857 | 1.028 |
| 0x16 | 0.87 | 1.044 |
| 0x17 | 0.883 | 1.060 |
| 0x18 | 0.896 | 1.075 |
| 0x19 | 0.909 | 1.091 |
| 0x1A | 0.922 | 1.106 |
| 0x1B | 0.935 | 1.122 |
| 0x1C | 0.948 | 1.138 |
| 0x1D | 0.961 | 1.153 |
| 0x1E | 0.974 | 1.169 |
| 0x1F | 0.987 | 1.184 |
| 0x00 | 1 | 1.200 |
| 0x01 | 1.013 | 1.216 |
| 0x02 | 1.026 | 1.231 |
| 0x03 | 1.039 | 1.247 |
| 0x04 | 1.052 | 1.262 |
| 0x05 | 1.065 | 1.278 |
| 0x06 | 1.078 | 1.294 |
| 0x07 | 1.091 | 1.309 |
| 0x08 | 1.104 | 1.325 |
| 0x09 | 1.117 | 1.340 |
| 0x0A | 1.13 | 1.356 |
| 0x0B | 1.143 | 1.372 |
| 0x0C | 1.156 | 1.387 |
| 0x0D | 1.169 | 1.403 |
| 0x0E | 1.182 | 1.418 |
| 0x0F | 1.195 | 1.434 |
| 0x10 | 1.208 | 1.450 |
| 0x11 | 1.221 | 1.465 |
| 0x12 | 1.234 | 1.481 |
| 0x13 | External | External x 1.2 |

## APPLICATIONS INFORMATION

## DESIGN GUIDELINES

Before starting design and layout of the AD9284 as a system, it is recommended that the designer become familiar with these guidelines, which discuss the special circuit connections and layout requirements that are needed for certain pins.

## Power and Ground Recommendations

When connecting power to the AD9284, it is strongly recommended that two separate supplies be used. Use one 1.8 V supply for analog (AVDD); use a separate 1.8 V supply for the digital output supply (DRVDD). If a common 1.8 V AVDD and DRVDD supply must be used, the AVDD and DRVDD domains must be isolated with a ferrite bead or filter choke and separate decoupling capacitors. Several different decoupling capacitors can be used to cover both high and low frequencies. Locate these capacitors close to the point of entry at the printed circuit board (PCB) level and close to the pins of the part, with minimal trace length.
A single PCB ground plane should be sufficient when using the AD9284. With proper decoupling and smart partitioning of the PCB analog, digital, and clock sections, optimum performance is easily achieved.
Exposed Paddle Thermal Heat Sink Recommendations
The exposed paddle ( $\operatorname{Pin} 0$ ) is the only ground connection for the AD9284; therefore, it must be connected to analog ground (AGND) on the customer PCB. To achieve the best electrical and thermal performance, mate an exposed (no solder mask), continuous copper plane on the PCB to the AD9284 exposed paddle, Pin 0.
The copper plane should have several vias to achieve the lowest possible resistive thermal path for heat dissipation to flow through the bottom of the PCB. Fill or plug these vias with nonconductive epoxy.

To maximize the coverage and adhesion between the ADC and the PCB, a silkscreen should be overlaid to partition the continuous plane on the PCB into several uniform sections. This provides several tie points between the ADC and the PCB during the reflow process. Using one continuous plane with no partitions guarantees only one tie point between the ADC and the PCB. For detailed information about packaging and PCB layout of chip scale packages, see the AN-772 Application Note, A Design and Manufacturing Guide for the Lead Frame Chip Scale Package (LFCSP), at www.analog.com.

## VCM

The VCM pin should be decoupled to ground with a $0.1 \mu \mathrm{~F}$ capacitor.

## RBIAS

The AD9284 requires that a $10 \mathrm{k} \Omega$ resistor be placed between the RBIAS pin and ground. This resistor, which sets the master current reference of the ADC core, should have at least a $1 \%$ tolerance.

## Reference Decoupling

Decouple the VREF pin externally to ground with a low ESR, $1.0 \mu \mathrm{~F}$ capacitor in parallel with a low ESR, $0.1 \mu \mathrm{~F}$ ceramic capacitor.

## SPI Port

The SPI port should not be active during periods when the full dynamic performance of the converter is required. Because the SCLK, CSB, and SDIO signals are typically asynchronous to the ADC clock, noise from these signals can degrade converter performance. If the on-board SPI bus is used for other devices, it may be necessary to provide buffers between this bus and the AD9284 to prevent these signals from transitioning at the converter inputs during critical sampling periods.

## OUTLINE DIMENSIONS


*COMPLIANT TO JEDEC STANDARDS MO-220-VKKD-2
WITH EXCEPTION TO EXPOSED PAD DIMENSION
Figure 26. 48-Lead Lead Frame Chip Scale Package [LFCSP_VQ]
$7 \mathrm{~mm} \times 7 \mathrm{~mm}$ Body, Very Thin Quad (CP-48-12)
Dimensions shown in millimeters

## ORDERING GUIDE

| Model $^{1}$ | Temperature <br> Range | Package Description | Package <br> Option |
| :--- | :--- | :--- | :--- |
| AD9284BCPZ-250 | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | 48-Lead Lead Frame Chip Scale Package [LFCSP_VQ] | CP-48-12 |
| AD9284BCPZRL7-250 | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ | 48-Lead Lead Frame Chip Scale Package [LFCSP_VQ] <br> Evaluation Board | CP-48-12 |
| AD9284-250EBZ |  |  |  |

## NOTES


[^0]:    ${ }^{1}$ See the AN-835 Application Note, Understanding High Speed ADC Testing and Evaluation, for a complete set of definitions and an explanation of how these tests were completed.
    ${ }^{2}$ Measured with a low frequency, full-scale sine wave, with approximately 5 pF loading on each output bit.

[^1]:    ${ }^{1}$ See the AN-835 Application Note, Understanding High Speed ADC Testing and Evaluation, for a complete set of definitions and an explanation of how these tests were completed.
    ${ }^{2}$ Specified for LVDS and LVPECL only.

